

TO-252 N Channel Enhancement 沟道增强型 MOS Field Effect Transistor 场效应管

■ Features 特点

Low Gate Charge 低电荷密度

$R_{DS(ON)}=2000\text{m}\Omega$ (Type)@ $V_{GS}=10\text{V}$

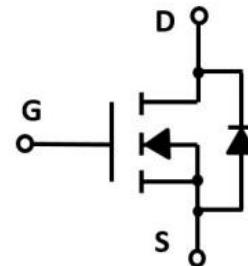
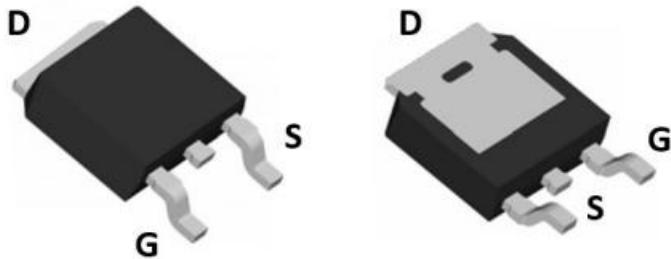
■ Applications 应用

Fast switch 快速开关

DC/DC Converter 升压转换

PWM Application 脉宽调制应用

■ Internal Schematic Diagram 内部结构



■ Absolute Maximum Ratings 最大额定值

Characteristic 特性参数	Symbol 符号	Rating 额定值	Unit 单位
Drain-Source Voltage 漏极-源极电压	BV_{DSS}	650	V
Gate- Source Voltage 栅极-源极电压	V_{GS}	± 30	V
Drain Current (continuous)漏极电流-连续	I_D	4	A
Drain Current (pulsed)漏极电流-脉冲	I_{DM}	16	A
Total Device Dissipation 总耗散功率	P_D	33	W
Avalanche Energy Single Pulse 雪崩能量	E_{AS}	112	mJ
Thermal Resistance Junction 热阻	$R_{\theta JA}$	3.8	°C/W
Junction/Storage Temperature 结温/储存温度	T_J, T_{stg}	-55~150	°C



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FSD4N65

■ Electrical Characteristics 电特性

($T_A=25^\circ\text{C}$ unless otherwise noted 如无特殊说明, 温度为 25°C)

Characteristic 特性参数	Symbol 符号	Min 最小值	Typ 典型值	Max 最大值	Unit 单位
Drain-Source Breakdown Voltage 漏极-源极击穿电压($I_D=250\mu\text{A}, V_{GS}=0\text{V}$)	BV_{DSS}	650	—	—	V
Gate Threshold Voltage 栅极开启电压($I_D=250\mu\text{A}, V_{GS}=V_{DS}$)	$V_{GS(\text{th})}$	2	3	4	V
Zero Gate Voltage Drain Current 零栅压漏极电流($V_{GS}=0\text{V}, V_{DS}=650\text{V}$)	I_{DSS}	—	—	10	μA
Gate Body Leakage 栅极漏电流($V_{GS}=\pm30\text{V}, V_{DS}=0\text{V}$)	I_{GSS}	—	—	± 100	nA
Static Drain-Source On-State Resistance 静态漏源导通电阻($I_D=2\text{A}, V_{GS}=10\text{V}$)	$R_{DS(\text{ON})}$	—	2000	2400	$\text{m}\Omega$
Diode Forward Voltage Drop 内附二极管正向压降($I_{SD}=4\text{A}, V_{GS}=0\text{V}$)	V_{SD}	—	—	1.4	V
Input Capacitance 输入电容 ($V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$)	C_{ISS}	—	520	—	pF
Common Source Output Capacitance 共源输出电容($V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$)	C_{OSS}	—	70	—	pF
Reverse Transfer Capacitance 反馈电容 ($V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$)	C_{RSS}	—	8	—	pF
Total Gate Charge 栅极电荷密度 ($V_{DS}=520\text{V}, I_D=4\text{A}, V_{GS}=10\text{V}$)	Q_g	—	15	—	nC
Gate Source Charge 栅源电荷密度 ($V_{DS}=520\text{V}, I_D=4\text{A}, V_{GS}=10\text{V}$)	Q_{gs}	—	3	—	nC
Gate Drain Charge 栅漏电荷密度 ($V_{DS}=520\text{V}, I_D=4\text{A}, V_{GS}=10\text{V}$)	Q_{gd}	—	8	—	nC
Turn-ON Delay Time 开启延迟时间 ($V_{DS}=325\text{V} I_D=4\text{A}, R_{\text{GEN}}=25\Omega, V_{GS}=10\text{V}$)	$t_{d(on)}$	—	13	—	ns
Turn-ON Rise Time 开启上升时间 ($V_{DS}=325\text{V} I_D=4\text{A}, R_{\text{GEN}}=25\Omega, V_{GS}=10\text{V}$)	t_r	—	45	—	ns
Turn-OFF Delay Time 关断延迟时间 ($V_{DS}=325\text{V} I_D=4\text{A}, R_{\text{GEN}}=25\Omega, V_{GS}=10\text{V}$)	$t_{d(off)}$	—	25	—	ns
Turn-OFF Fall Time 关断下降时间 ($V_{DS}=325\text{V} I_D=4\text{A}, R_{\text{GEN}}=25\Omega, V_{GS}=10\text{V}$)	t_f	—	35	—	ns

■ Typical Characteristic Curve 典型特性曲线

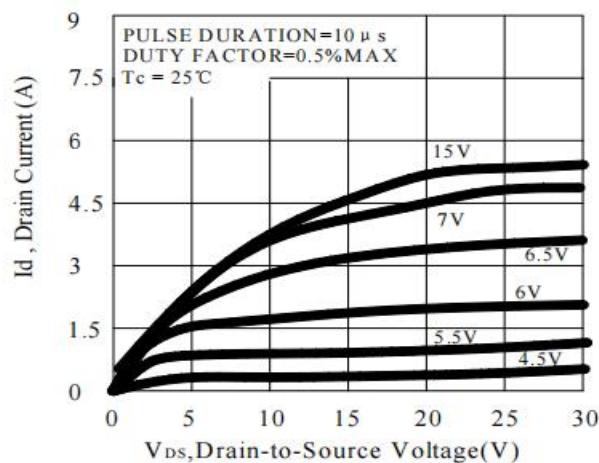


Figure 1: Output Characteristics

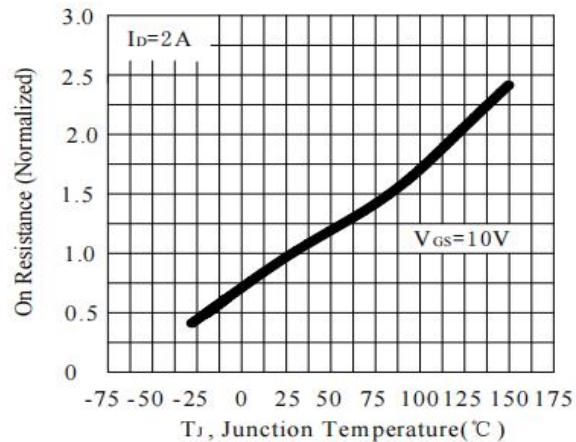


Figure 3: On-Resistance vs. T_J

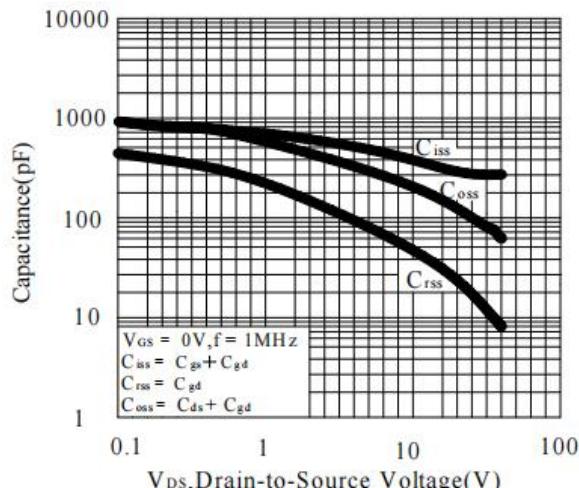


Figure 5: Capacitance Characteristics

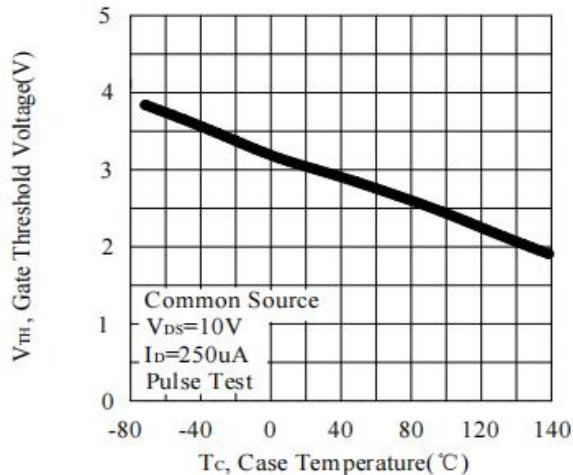


Figure 2: Threshold Voltage Characteristics

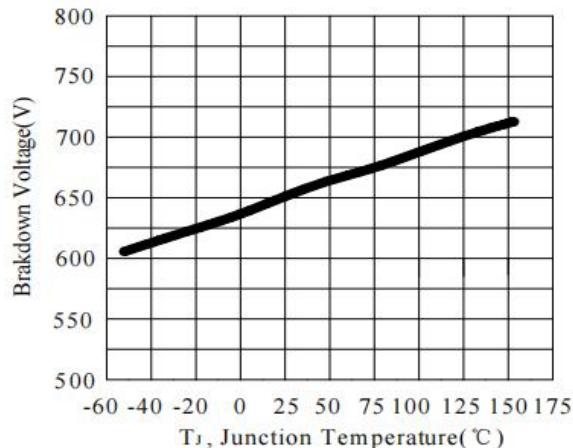


Figure 4: Breakdown Voltage vs. T_J

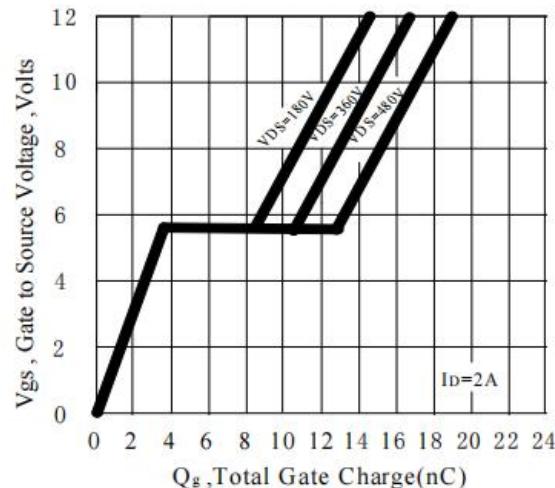


Figure 6: Gate-Charge Characteristics

■ Typical Characteristic Curve 典型特性曲线

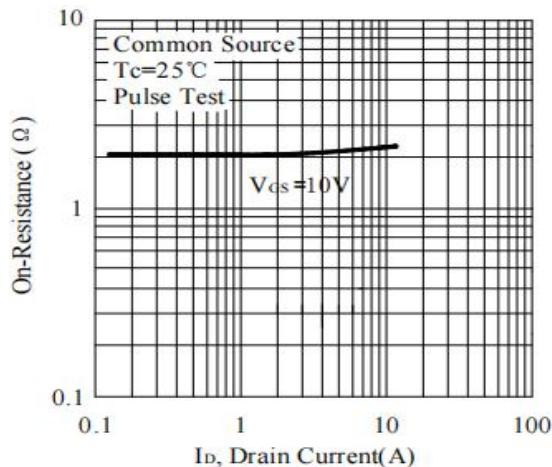


Figure 7: On-Resistance vs. Drain Current

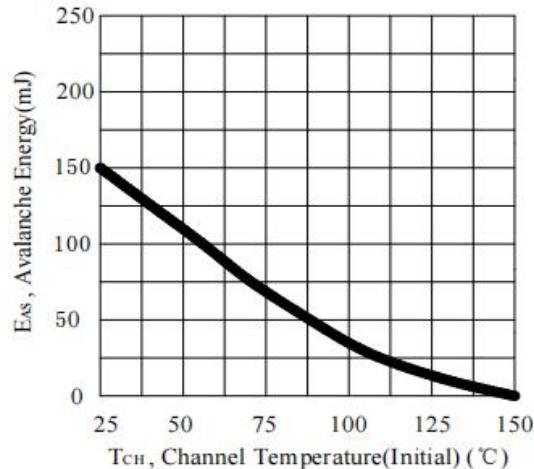


Figure 8: Avalanche Energy Characteristics

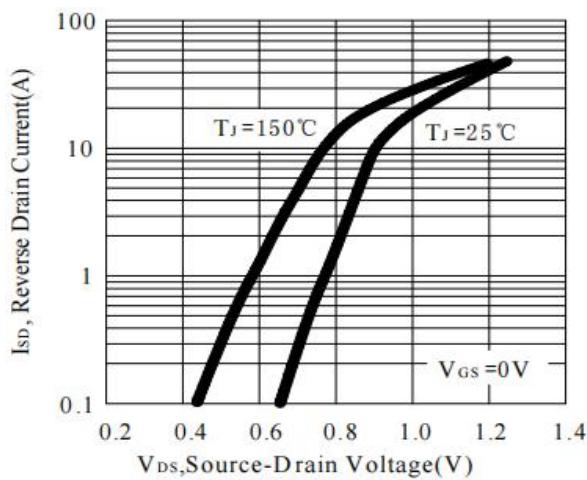


Figure 9: Diode Characteristics

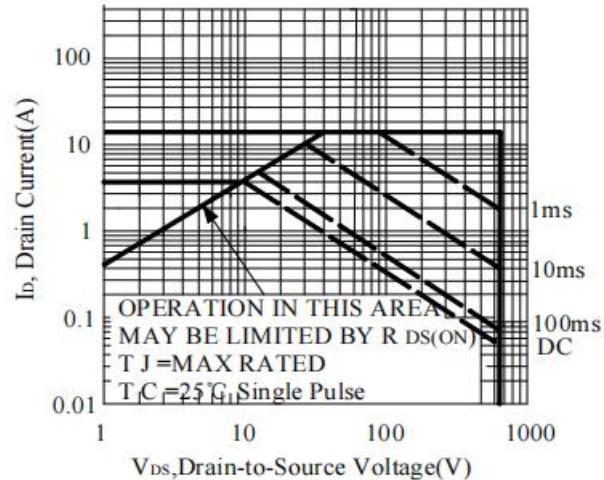


Figure 10: Safe Operating Area

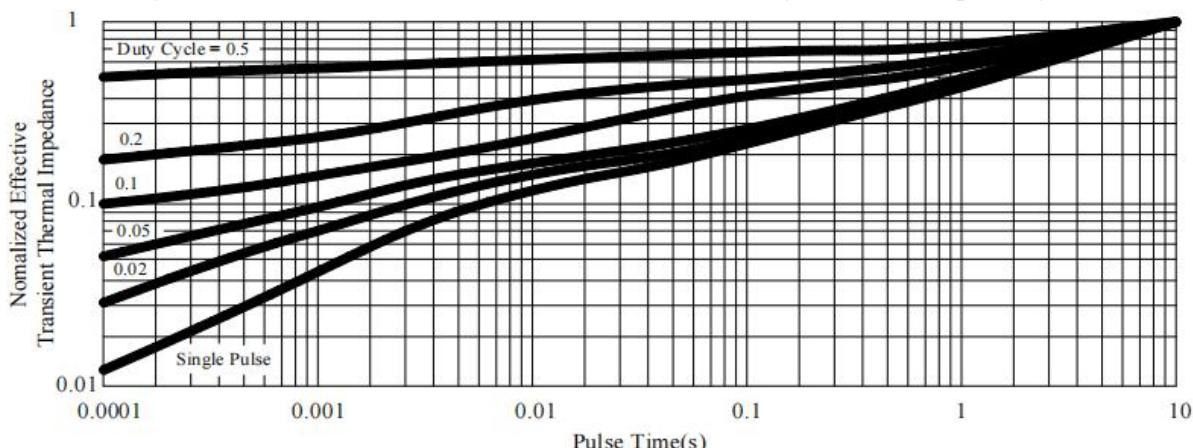
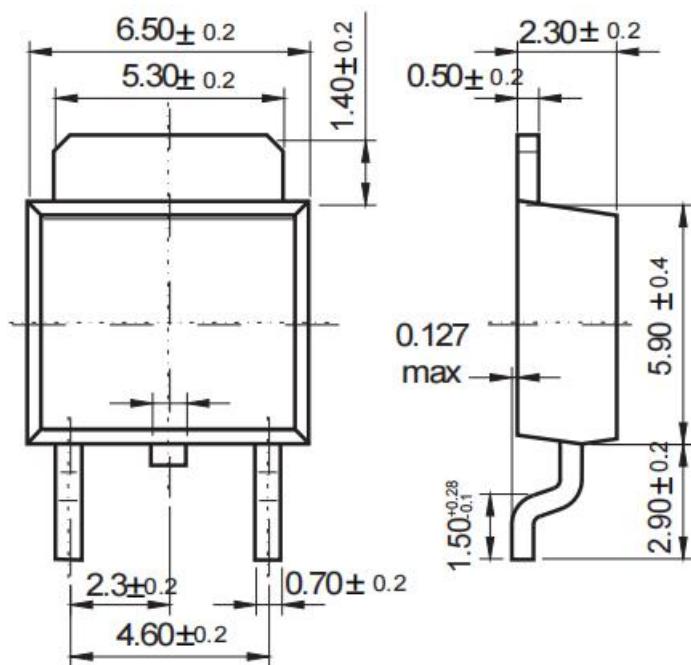


Figure 11: Transient Thermal Response Curve

■ Package Dimension 外形封装尺寸

TO-252

Unit: mm



Dimensions in inches and (millimeters)